

January 2001

Si9926DY

Dual N-Channel 2.5V Specified PowerTrench® MOSFET

General Description

These N-Channel 2.5V specified MOSFETs use Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V – 10V).

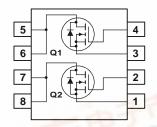
Applications

- Battery protection
- Load switch
- Power management

Features

- 6.5 A, 20 V. $R_{DS(ON)} = 0.030 \ \Omega \ @ \ V_{GS} = 4.5 \ V$ $R_{DS(ON)} = 0.043 \ \Omega \ @ \ V_{GS} = 2.5 \ V.$
- · Optimized for use in battery protection circuits
- ±10 V_{GSS} allows for wide operating voltage range
- Low gate charge





Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		±10	V
I _D	Drain Current - Continuous	(Note 1a)	6.5	А
	- Pulsed		20	
P _D	Power Dissipation for Dual Operation		2	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	7 TOY
		(Note 1b)	1	-C.C.C
		(Note 1c)	0.9	D.L
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
9926	Si9926DY	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		14		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 8 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I_{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -8 \text{ V}$ $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	0.5	1	1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 4.5 \text{ V}, \qquad I_D = 6.5 \text{ A} $ $V_{GS} = 2.5 \text{ V}, \qquad I_D = 5.4 \text{ A} $ $V_{GS} = 4.5 \text{ V}, I_D = 6.5 \text{ A}, T_J = 125 ^{\circ}\text{C}$		0.025 0.036 0.035	0.030 0.043 0.050	Ω
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	15			Α
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_D = 3 \text{ A}$		11		S
Dvnamio	Characteristics			•	•	
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, \qquad V_{GS} = 0 \text{ V},$ f = 1.0 MHz		700		pF
C _{oss}	Output Capacitance			175		pF
C _{rss}	Reverse Transfer Capacitance	7		85		pF
Switchin	g Characteristics (Note 2)			•	•	
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 10 \text{ V}, \qquad I_D = 1 \text{ A},$		8	16	ns
t _r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	18	ns
t _{d(off)}	Turn-Off Delay Time	7		18	29	ns
t _f	Turn-Off Fall Time	7		5	10	ns
Qg	Total Gate Charge	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 3A,$		7	10	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 4.5 V		1.2		nC
Q_{gd}	Gate-Drain Charge	7		1.9		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings	•			•
Is	Maximum Continuous Drain–Source				1.3	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A} \text{(Note 2)}$		0.65	1.2	V

Notes

1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 78°/W when mounted on a 0.5in² pad of 2 oz copper



b) 125°/W when mounted on a 0.02 in² pad of 2 oz copper



c) 135°/W when mounted on a minimum pad.

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

Typical Characteristics

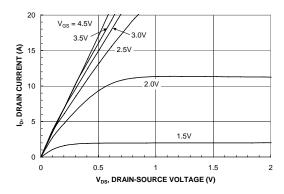


Figure 1. On-Region Characteristics.

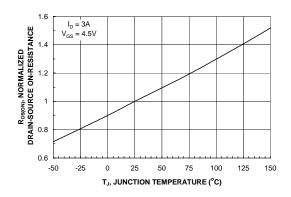


Figure 3. On-Resistance Variation with Temperature.

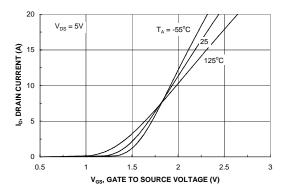


Figure 5. Transfer Characteristics.

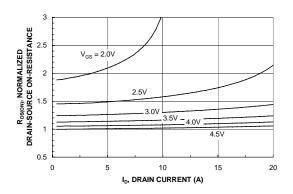


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

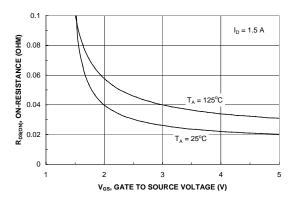


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

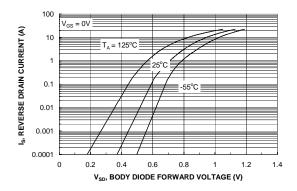
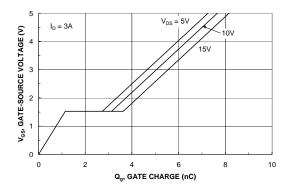


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



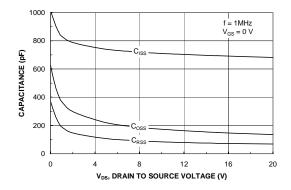


Figure 7. Gate Charge Characteristics.

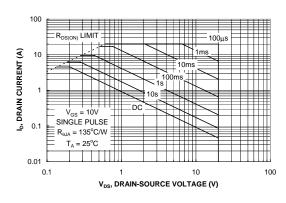


Figure 8. Capacitance Characteristics.

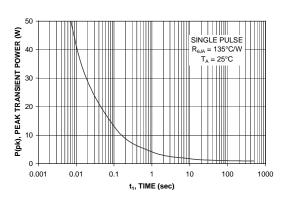


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

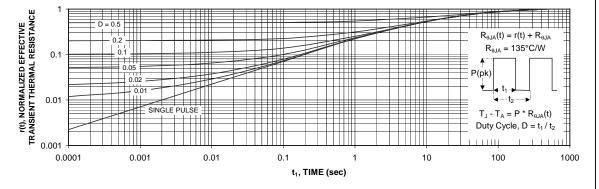


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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